

N-channel 600 V, 0.110 Ω typ., 26 A MDmesh™ M2 EP Power MOSFET in a TO-220 package

Datasheet - production data

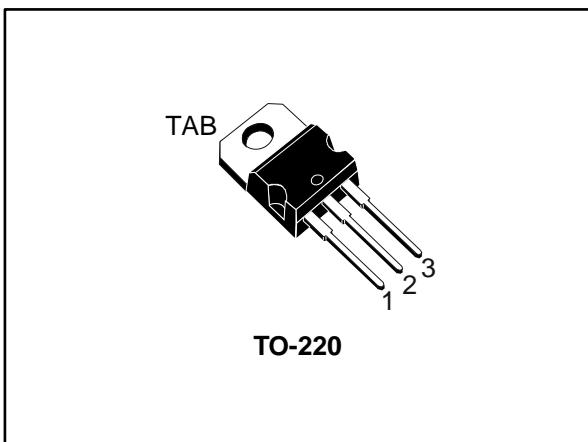


Figure 1: Internal schematic diagram

Features

Order code	$V_{DS} @ T_{Jmax}$	$R_{DS(on)} \text{ max.}$	I_D
STP35N60M2-EP	650 V	0.130 Ω	26 A

- Extremely low gate charge
- Excellent output capacitance (C_{oss}) profile
- Very low turn-off switching losses
- 100% avalanche tested
- Zener-protected

Applications

- Switching applications
- Tailored for very high-frequency converters ($f > 150$ kHz)

Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STP35N60M2-EP	35N60M2EP	TO-220	Tube

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	± 25	V
I_D	Drain current (continuous) at $T_C = 25^\circ\text{C}$	26	A
I_D	Drain current (continuous) at $T_C = 100^\circ\text{C}$	16	A
$I_{DM}^{(1)}$	Drain current (pulsed)	70	A
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	190	W
$dv/dt^{(2)}$	Peak diode recovery	15	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	V/ns
T_{stg}	Storage temperature range	-55 to 150	$^\circ\text{C}$
T_j	Operating junction temperature range		

Notes:

(1) Pulse width is limited by safe operating area.

(2) $I_{SD} \leq 26$ A, $di/dt \leq 400$ A/ μs , V_{DS} peak < $V_{(BR)DSS}$, $V_{DD} = 400$ V(3) $V_{DS} \leq 480$ V

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	0.66	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient	62.5	$^\circ\text{C}/\text{W}$

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_{jmax})	5	A
E_{AS}	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50$ V)	500	mJ

2 Electrical characteristics

$T_C = 25^\circ\text{C}$ unless otherwise specified

Table 5: On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}$, $I_D = 1 \text{ mA}$	600			V
I_{DSS}	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}$, $V_{DS} = 600 \text{ V}$			1	μA
		$V_{GS} = 0 \text{ V}$, $V_{DS} = 600 \text{ V}$, $T_C = 125^\circ\text{C}$ ⁽¹⁾			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}$, $V_{GS} = \pm 25 \text{ V}$			± 10	μA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}$, $I_D = 13 \text{ A}$		0.110	0.130	Ω

Notes:

⁽¹⁾Defined by design, not subject to production test

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 100 \text{ V}$, $f = 1 \text{ MHz}$, $V_{GS} = 0 \text{ V}$	-	1750	-	pF
C_{oss}	Output capacitance		-	97	-	pF
C_{rss}	Reverse transfer capacitance		-	2.5	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0$ to 480 V , $V_{GS} = 0 \text{ V}$	-	204	-	pF
R_G	Intrinsic gate resistance	$f = 1 \text{ MHz}$, $I_D = 0 \text{ A}$	-	5	-	Ω
Q_g	Total gate charge	$V_{DD} = 480 \text{ V}$, $I_D = 26 \text{ A}$, $V_{GS} = 0$ to 10 V (see Figure 16: "Test circuit for gate charge behavior")	-	41	-	nC
Q_{gs}	Gate-source charge		-	7	-	nC
Q_{gd}	Gate-drain charge		-	20	-	nC

Notes:

⁽¹⁾ $C_{oss \text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 7: Switching energy

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$E_{(off)}$	Turn-off energy (from 90% V_{GS} to 0% I_D)	$V_{DD} = 400 \text{ V}$, $I_D = 4 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$	-	22	-	μJ
		$V_{DD} = 400 \text{ V}$, $I_D = 10 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$	-	44	-	μJ

Table 8: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}$, $I_D = 13 \text{ A}$, $R_G = 4.7 \Omega$, $V_{GS} = 10 \text{ V}$ (see Figure 15: "Test circuit for resistive load switching times" and Figure 20: "Switching time waveform")	-	16.5	-	ns
t_r	Rise time		-	13.5	-	ns
$t_{d(off)}$	Turn-off-delay time		-	70	-	ns
t_f	Fall time		-	7	-	ns

Table 9: Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		26	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		70	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$, $I_{SD} = 26 \text{ A}$	-		1.6	V
t_{rr}	Reverse recovery time	$I_{SD} = 26 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$ (see Figure 17: "Test circuit for inductive load switching and diode recovery times")	-	273		ns
Q_{rr}	Reverse recovery charge		-	3.6		μC
I_{RRM}	Reverse recovery current		-	26.5		A
t_{rr}	Reverse recovery time	$I_{SD} = 26 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$, $V_{DD} = 60 \text{ V}$, $T_j = 150 \text{ }^\circ\text{C}$ (see Figure 17: "Test circuit for inductive load switching and diode recovery times")	-	400		ns
Q_{rr}	Reverse recovery charge		-	6.3		μC
I_{RRM}	Reverse recovery current		-	31.5		A

Notes:

(1)Pulse width is limited by safe operating area.

(2)Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

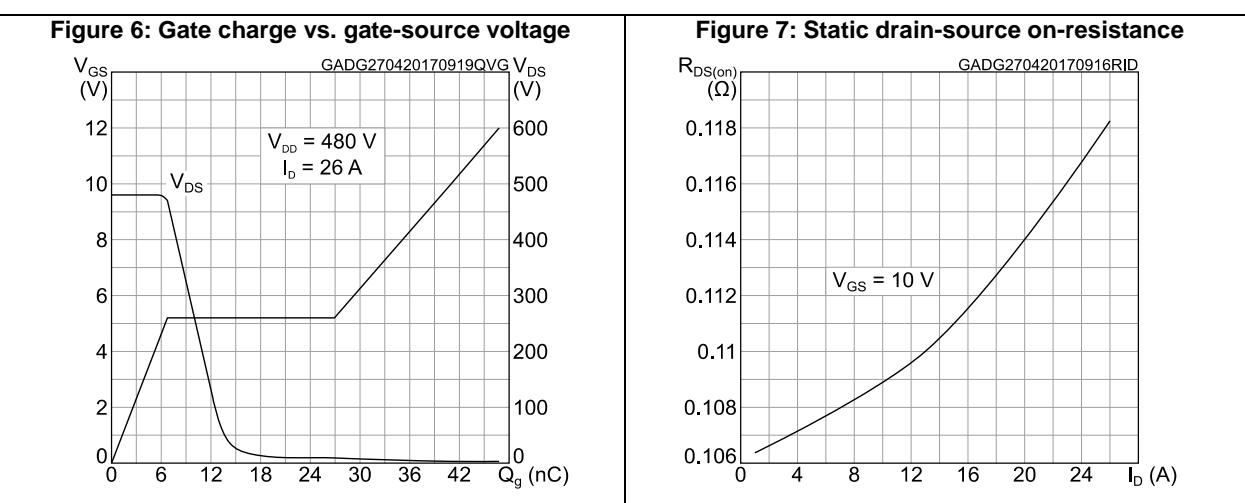
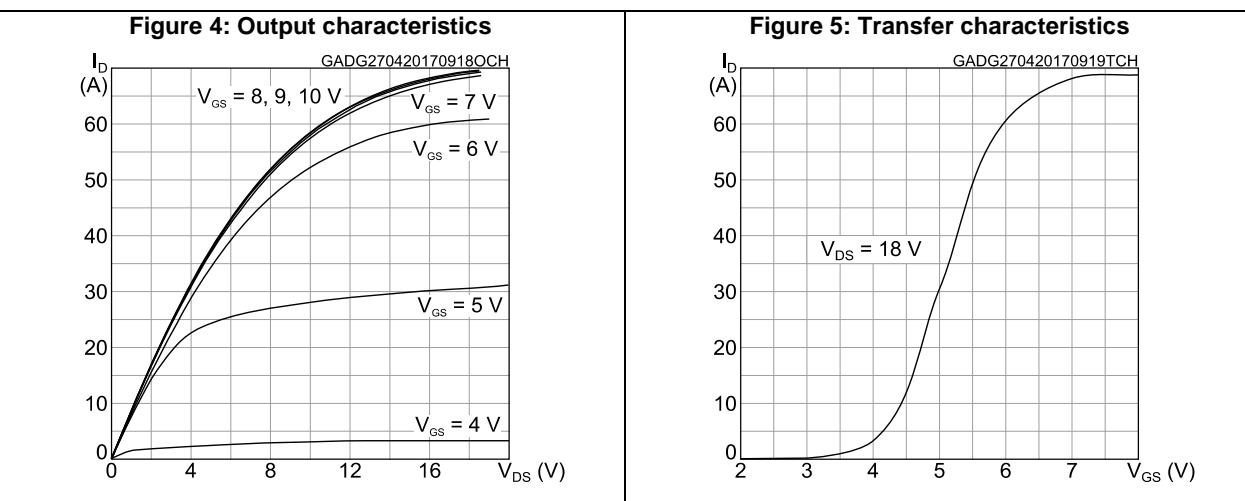
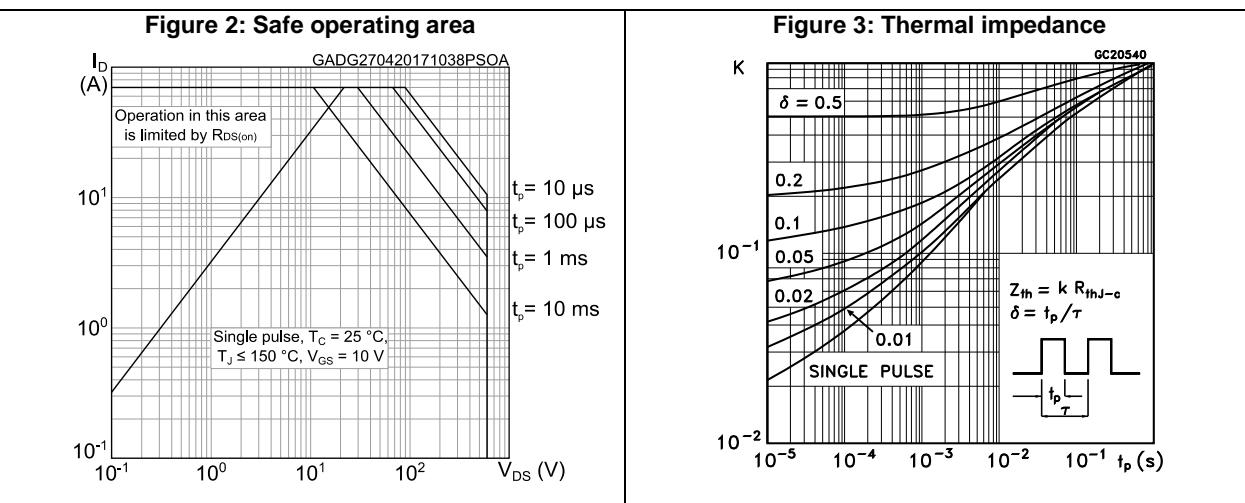


Figure 8: Capacitance variations

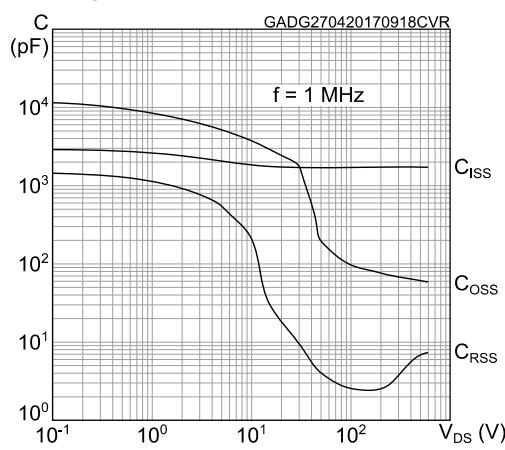


Figure 9: Output capacitance stored energy

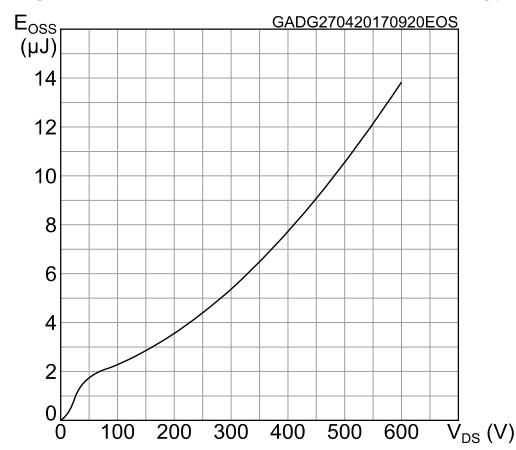


Figure 10: Turn-off switching energy vs. drain current

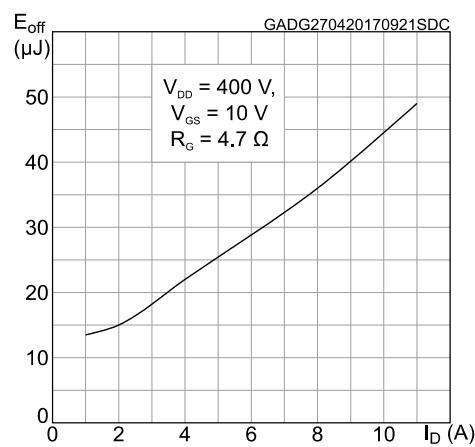


Figure 11: Normalized gate threshold voltage vs. temperature

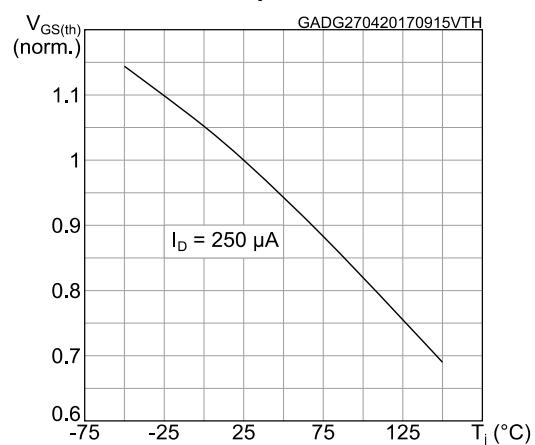


Figure 12: Normalized on-resistance vs. temperature

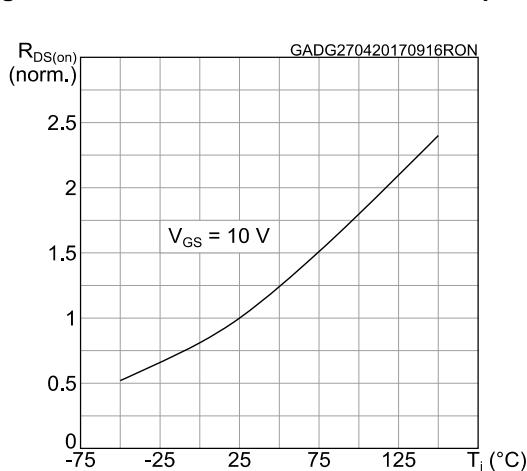


Figure 13: Source-drain diode forward characteristics

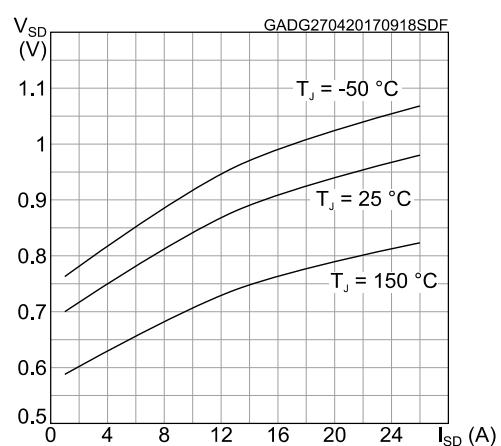
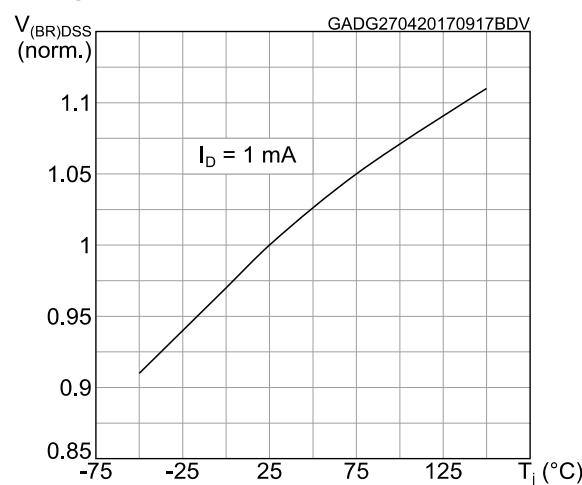


Figure 14: Normalized $V_{(BR)DSS}$ vs. temperature

3 Test circuits

Figure 15: Test circuit for resistive load switching times

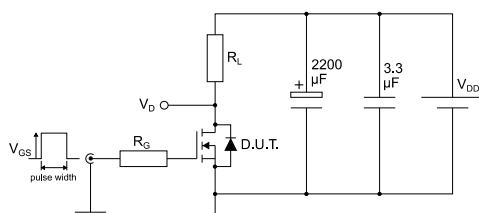


Figure 16: Test circuit for gate charge behavior

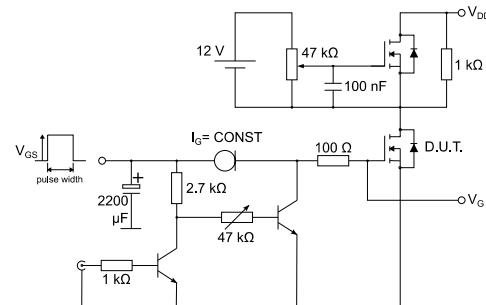


Figure 17: Test circuit for inductive load switching and diode recovery times

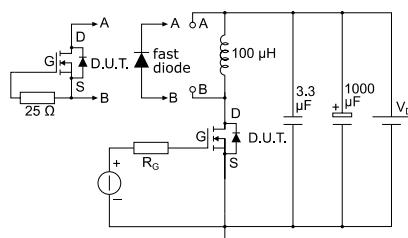


Figure 18: Unclamped inductive load test circuit

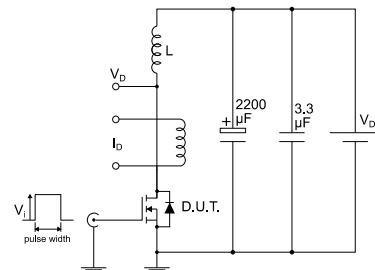


Figure 19: Unclamped inductive waveform

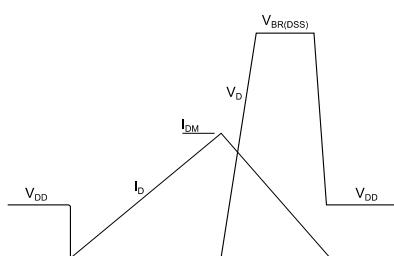
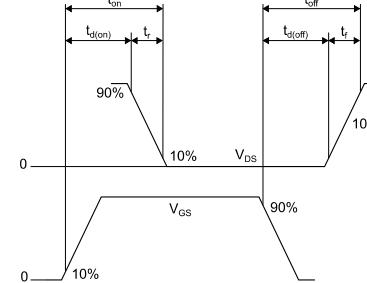


Figure 20: Switching time waveform

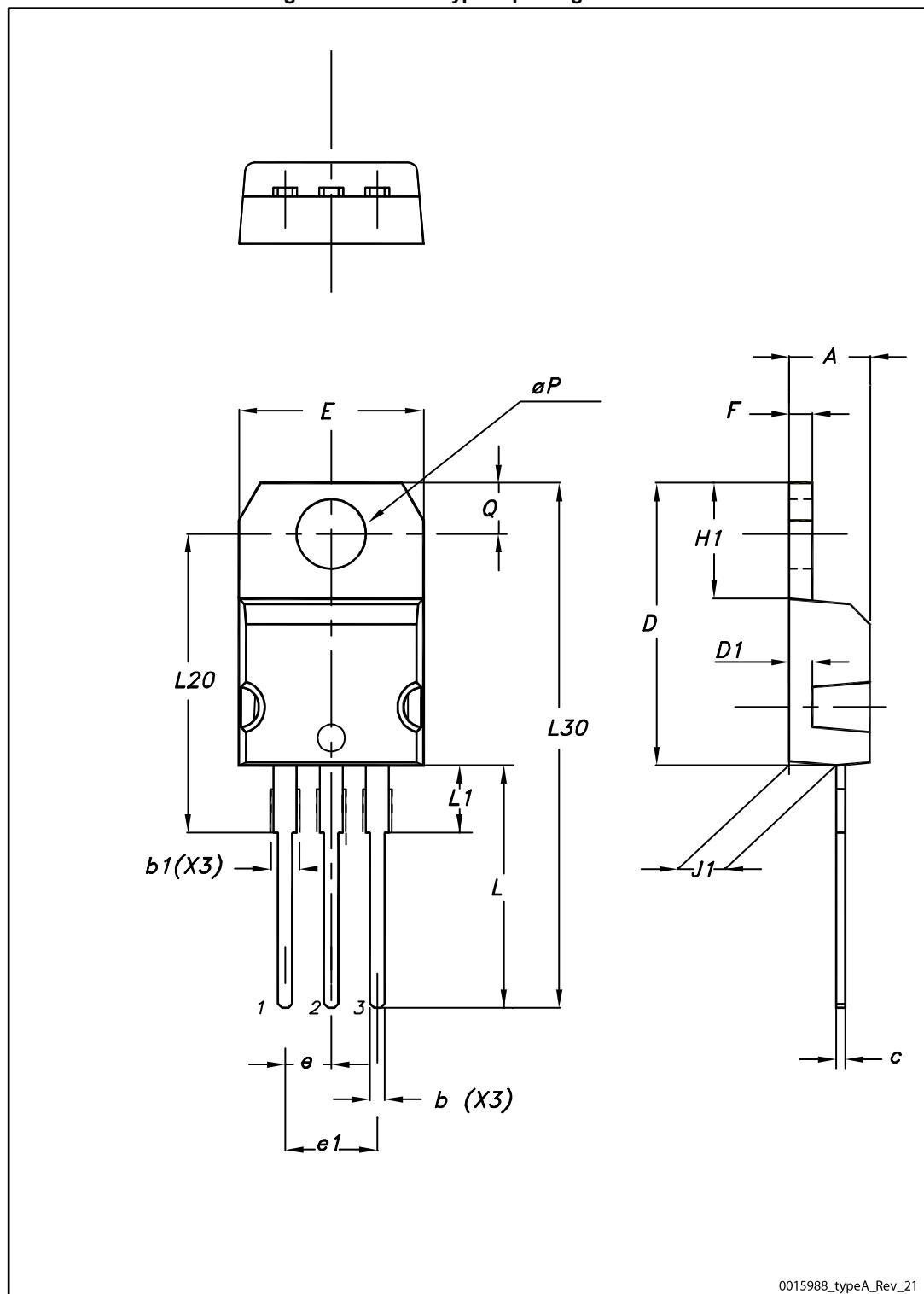


4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 TO-220 type A package information

Figure 21: TO-220 type A package outline



0015988_typeA_Rev_21

Table 10: TO-220 type A package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95

5 Revision history

Table 11: Document revision history

Date	Revision	Changes
02-May-2017	1	First release

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